



EMI TEST REPORT

Test Report No. : 32HE0178-HO-B

Applicant : SHARP CORPORATION
Type of Equipment : Cellular Phone
Model No. : SH-07D
FCC ID : APYHRO00168
Test standard : FCC Part 15 Subpart B: 2012 Class B
Test Result : Complied

1. This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.
2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
5. This test report must not be used by the customer product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.

Date of test:

April 16, 2012

Representative test engineer:

Hironobu Ohnishi
Engineer of WiSE Japan,
UL Verification Service

Approved by:

Masanori Nishiyama
Leader of WiSE Japan,
UL Verification Service



NVLAP LAB CODE: 200572-0

This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation. *As for the range of Accreditation in NVLAP, you may refer to the WEB address, <http://www.ul.com/japan/jpn/pages/services/emc/about/mark1/index.jsp#nvlap>

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8116

Facsimile : +81 596 24 8124

13-EM-F0429

CONTENTS	PAGE
SECTION 1: Customer information	3
SECTION 2: Equipment under test (E.U.T.)	3
SECTION 3: Test specification, procedures & results	4
SECTION 4: Operation of E.U.T. during testing	7
SECTION 5: Conducted Emission	9
SECTION 6: Radiated Emission	10
APPENDIX 1: Data of EMI test	11
Conducted Emission.....	11
Radiated Emission.....	13
APPENDIX 2: Test instruments	17
APPENDIX 3: Photographs of test setup.....	18
Conducted Emission.....	18
Radiated Emission.....	19
Worst Case Position (Horizontal: X-axis/ Vertical:X-axis)	21

SECTION 1: Customer information

Company Name : SHARP CORPORATION
Address : 2-13-1 Iida, Hachihonmatsu, Higashi-Hiroshima City, Hiroshima,
739-0192 Japan
Telephone Number : +81-82-420-1825
Facsimile Number : +81-82-420-1829
Contact Person : Kazuo Sugimoto

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Cellular Phone
Model No. : SH-07D
Serial No. : Refer to Section 4, Clause 4.2
Receipt Date of Sample : April 7, 2012
Country of Mass-production : Japan
Condition of EUT : Production prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No Modification by the test lab

2.2 Product description

Feature of EUT : Five Band WCDMA(FDD: I / V / VI / IX / XIX) and Tri-band
GSM(900 / 1800 / 1900)
Dual mode Cellular Phone / Bluetooth/W-LAN, Felica & 1.5GHz Band
Satellite Receiver (GPS) enable
- GSM (EU: 900 / 1800M, 1900M)
- WCDMA (EU: 2000M, US: 850M, JPN: 800 / 1700 / 2000)
Clock frequency(ies) in the system : CPU: 1.0GHz
Source oscillation:48MHz

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8116

Facsimile : +81 596 24 8124

SECTION 3: Test specification, procedures & results

3.1 Test specification

Test Specification : FCC Part 15 Subpart B: 2012, final revised on February 1, 2012

Title : FCC 47CFR Part15 Radio Frequency Device
Subpart B Unintentional Radiators

3.2 Procedures and results

Item	Test Procedure	Limits	Deviation	Worst margin	Result
Conducted emission	FCC: ANSI C63.4: 2003 7. AC powerline conducted emission measurements	Class B	N/A	[QP] 11.8dB 3.80080MHz, L [AV] 14.2dB 0.17541MHz, N	Complied
Radiated emission	FCC: ANSI C63.4: 2003 8. Radiated emission measurements	Class B	N/A	6.7dB 798.300MHz, Vertical, QP	Complied

*Note: UL Japan, Inc's EMI Work Procedure 13-EM-W0420.

3.3 Addition to standard

No addition, exclusion nor deviation has been made from the standard.

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8116

Facsimile : +81 596 24 8124

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room (semi-anechoic chamber)	Conducted emission (+dB)
	150kHz-30MHz
No.1	3.5dB
No.2	3.6dB
No.3	3.6dB
No.4	3.6dB

Test room (semi-anechoic chamber)	Radiated emission (10m*)(±dB)		
	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz
No.1	4.1dB	5.0dB	4.8dB
No.2	-	-	-
No.3	-	-	-
No.4	-	-	-

*10m = Measurement distance

Test room (semi-anechoic chamber)	Radiated emission						
	(3m*)(+dB)				(1m*)(+dB)		(0.5m*)(+dB)
	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz	1GHz -10GHz	10GHz -18GHz	18GHz -26.5GHz	26.5GHz -40GHz
No.1	4.2dB	5.0dB	5.1dB	4.7dB	5.7dB	4.4dB	4.3dB
No.2	4.1dB	5.2dB	5.1dB	4.8dB	5.6dB	4.3dB	4.2dB
No.3	4.5dB	5.0dB	5.2dB	4.8dB	5.6dB	4.5dB	4.2dB
No.4	4.7dB	5.2dB	5.2dB	4.8dB	5.6dB	5.1dB	4.2dB

*3m/1m/0.5m = Measurement distance

Conducted Emission test

The data listed in this test report has enough margin, more than the site margin.

Radiated emission test(3m)

The data listed in this test report has enough margin, more than the site margin.

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8116

Facsimile : +81 596 24 8124

3.5 Test Location

UL Japan, Inc. Head Office EMC Lab. *NVLAP Lab. code: 200572-0
4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN
Telephone : +81 596 24 8116 Facsimile : +81 596 24 8124

	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test set up, Data of EMI, and Test instruments

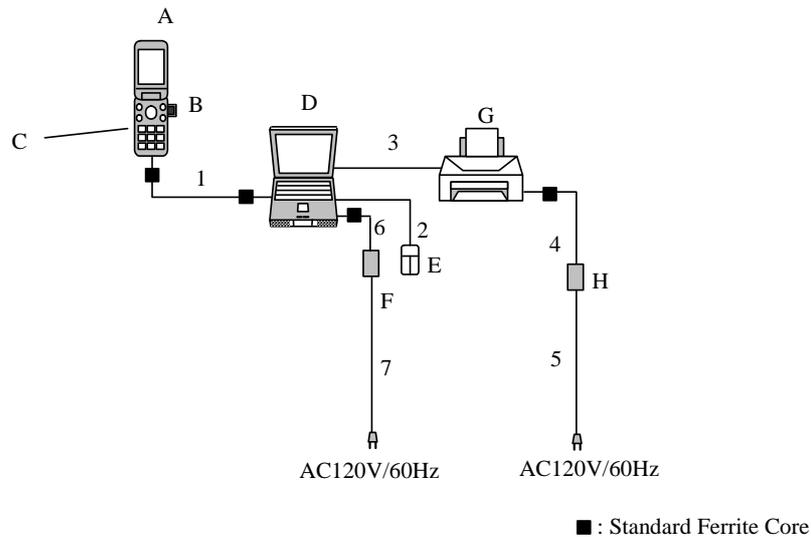
Refer to APPENDIX.

SECTION 4: Operation of E.U.T. during testing

4.1 Operating modes

The mode(s) : 1) USB Data Com Mode
The USB data is communicated between EUT and Personal computer (Pair of EUT).
2) Standby Mode
Standby state for USB communication.

4.2 Configuration and peripherals



* Cabling and setup were taken into consideration and test data was taken under worse case conditions.

Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Cellular Phone	SH-07D	004401113925149	SHARP CORPORATION	EUT
B	microSD Memory Card	SD-C08G	0852K93900Y	TOSHIBA	-
C	Lithium-Ion Battery	Battery Pack SH34	-	SHARP CORPORATION	EUT
D	Personal Computer	PP11L	CN-0D4571-48643-58P-1053	DELL	-
E	Mouse	M-UAG120	G83C0007F310	TOSHIBA	-
F	AC Adapter (PC)	PA-1650-05D2	CN-0F7970-71615-77H-0D63	DELL	-
G	Printer	C6410A	8G8BA1W18J	Hewlett Packard	-
H	AC Adapter(Printer)	AT-3018A-0101	C4557-60004	Hewlett Packard	-

List of cables used

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	USB Data Cable	1.15	Shielded	Shielded	-
2	Mouse Cable	0.71	Shielded	Shielded	-
3	Printer Cable	2.00	Shielded	Shielded	-
4	DC Power Cable(Printer)	2.00	Unshielded	Unshielded	-
5	AC Power Cable(Printer)	1.80	Unshielded	Unshielded	-
6	DC Power Cable(PC)	1.80	Unshielded	Unshielded	-
7	AC Power Cable(PC)	0.90	Unshielded	Unshielded	-

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8116

Facsimile : +81 596 24 8124

SECTION 5: Conducted Emission

5.1 Operating environment

Test place : No. 1 semi anechoic chamber.
Temperature : See data
Humidity : See data

5.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT and its peripherals was aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from the LISN/AMN and excess AC cable was bundled in center. I/O cables that were connected to the other peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. Each EUT current-carrying power lead, except the ground (safety) lead, was individually connected through a LISN/AMN to the input power source. All unused 50 ohm connectors of the LISN/AMN were resistivity terminated in 50 ohm when not connected to the measuring equipment. Photographs of the set up are shown in Appendix 3.

Frequency range : 0.15 MHz-30MHz
EUT position : Table top
EUT operation mode : See Clause 4.1

5.3 Test procedure

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT within a semi anechoic chamber. The EUT was connected to a Line Impedance Stabilization Network (LISN)/ Artificial Mains network (AMN). An overview sweep with peak detection has been performed. The measurements have been performed with a quasi-peak detector and if required, with an average detector.

The conducted emission measurements were made with the following detector function of the test receiver.

Detector Type : Quasi-Peak and Average
IF Bandwidth : 9 kHz

5.4 Test result

Summary of the test results: Pass

Date: April 16, 2012

Test engineer: Hironobu Ohnishi

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8116

Facsimile : +81 596 24 8124

SECTION 6: Radiated Emission

6.1 Operating environment

Test place : No. 1 semi anechoic chamber
Temperature : See data
Humidity : See data

6.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The EUT was set on the edge of the tabletop.
Test was made with the antenna positioned in both the horizontal and vertical planes of polarization. The measurement antenna was varied in height above the conducting ground plane to obtain the maximum signal strength. Photographs of the set up are shown in Appendix 3.

6.3 Test conditions

Frequency range : 30MHz-300MHz (Biconical antenna) / 300MHz-1000MHz (Logperiodic antenna)
1000MHz-6000MHz (Horn antenna)
Test distance : 3m
EUT position : Table top
EUT operation mode : See Clause 4.1

6.4 Test procedure

The height of the measuring antenna varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.
The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer.
The radiated emission measurements were made with the following detector function of the test receiver and the Spectrum analyzer.

Frequency	Below 1GHz	Above 1GHz
Instrument used	Test Receiver	Spectrum Analyzer
IF Bandwidth	QP: BW 120kHz	PK: RBW:1MHz/VBW: 3MHz AV *1): RBW:1MHz/VBW:10Hz

*1) When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

- The noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at representative X-axis since no difference was found among each position.

6.5 Test result

Summary of the test results: Pass

Date: April 16, 2012

Test engineer: Hironobu Ohnishi

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8116

Facsimile : +81 596 24 8124

APPENDIX 1: Data of EMI test

Conducted Emission

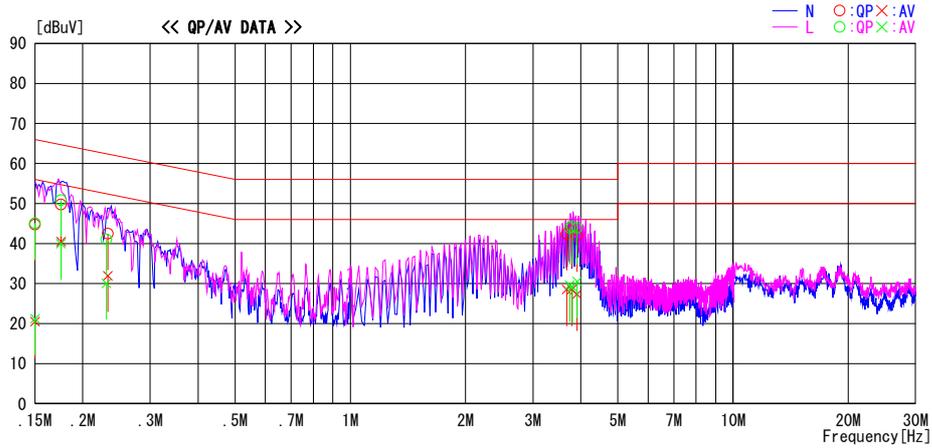
DATA OF CONDUCTED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2012/04/16

Report No. : 32HE0178-HO
Temp./Humi. : 24deg. C / 40% RH
Engineer : Hironobu Ohnishi

Mode / Remarks : USB Data Com Mode

LIMIT : FCC15.107(a) QP ClassB
FCC15.107(a) AV ClassB



Frequency [MHz]	Reading Level		Corr. Factor [dB]	Results		Limit		Margin		Phase	Comment
	QP [dBuV]	AV [dBuV]		QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]		
0.15000	31.5	7.3	13.2	44.7	20.5	66.0	56.0	21.3	35.5	N	
0.17541	36.5	27.3	13.2	49.7	40.5	64.7	54.7	15.0	14.2	N	
0.23250	29.2	18.7	13.3	42.5	32.0	62.4	52.4	19.9	20.4	N	
3.67601	28.6	14.7	13.8	42.4	28.5	56.0	46.0	13.6	17.5	N	
3.79120	29.4	14.7	13.8	43.2	28.5	56.0	46.0	12.8	17.5	N	
3.90830	28.2	13.5	13.8	42.0	27.3	56.0	46.0	14.0	18.7	N	
0.15000	31.9	8.0	13.2	45.1	21.2	66.0	56.0	20.9	34.8	L	
0.17536	37.6	26.8	13.2	50.8	40.0	64.7	54.7	13.9	14.7	L	
0.23050	27.7	16.8	13.3	41.0	30.1	62.4	52.4	21.4	22.3	L	
3.74280	30.1	15.8	13.8	43.9	29.6	56.0	46.0	12.1	16.4	L	
3.80080	30.4	15.4	13.8	44.2	29.2	56.0	46.0	11.8	16.8	L	
3.91493	30.1	16.7	13.8	43.9	30.5	56.0	46.0	12.1	15.5	L	

CHART: WITH FACTOR, Peak hold data. CALCULATION: RESULT=READING+C. F (LISN LOSS+ATT LOSS +CABLE LOSS)
Except for the above table : adequate margin data below the limits.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Conducted Emission

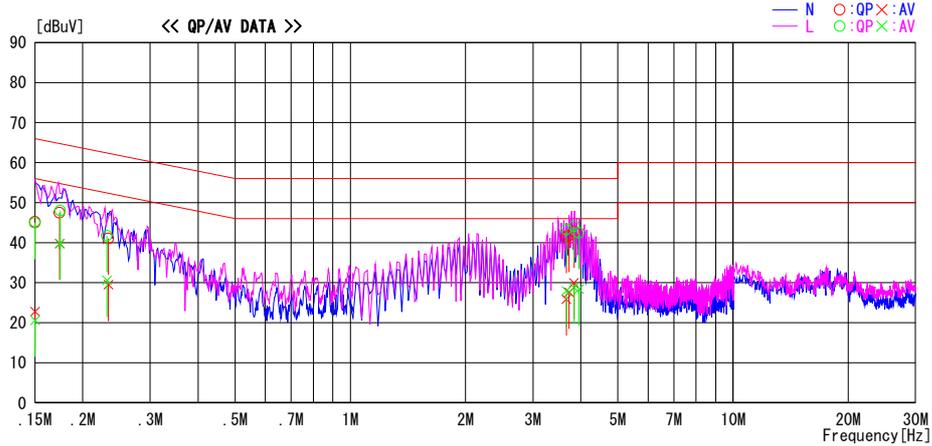
DATA OF CONDUCTED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2012/04/16

Report No. : 32HE0178-HO
Temp./Humi. : 24deg. C / 40% RH
Engineer : Hironobu Ohnishi

Mode / Remarks : Standby Mode

LIMIT : FCC15.107(a) QP ClassB
FCC15.107(a) AV ClassB



Frequency [MHz]	Reading		Corr. Factor [dB]	Results		Limit		Margin		Phase	Comment
	QP [dBuV]	AV [dBuV]		QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]		
0.15000	32.0	9.6	13.2	45.2	22.8	66.0	56.0	20.8	33.2	N	
0.17402	34.3	26.6	13.2	47.5	39.8	64.8	54.8	17.3	15.0	N	
0.23316	27.7	16.2	13.3	41.0	29.5	62.3	52.3	21.3	22.8	N	
3.66900	27.7	12.1	13.8	41.5	25.9	56.0	46.0	14.5	20.1	N	
3.72780	27.9	13.8	13.8	41.7	27.6	56.0	46.0	14.3	18.4	N	
3.84280	29.0	16.2	13.8	42.8	30.0	56.0	46.0	13.2	16.0	N	
0.15000	31.7	7.4	13.2	44.9	20.6	66.0	56.0	21.1	35.4	L	
0.17450	34.8	26.6	13.2	48.0	39.8	64.7	54.7	16.7	14.9	L	
0.23125	28.4	17.3	13.3	41.7	30.6	62.4	52.4	20.7	21.8	L	
3.66840	29.5	14.2	13.8	43.3	28.0	56.0	46.0	12.7	18.0	L	
3.84220	30.3	15.0	13.8	44.1	28.8	56.0	46.0	11.9	17.2	L	
3.95940	28.7	14.6	13.8	42.5	28.4	56.0	46.0	13.5	17.6	L	

CHART: WITH FACTOR, Peak hold data. CALCULATION: RESULT=READING+C. F (LISN LOSS+ATT LOSS +CABLE LOSS)
Except for the above table : adequate margin data below the limits.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission
(Below 1GHz)

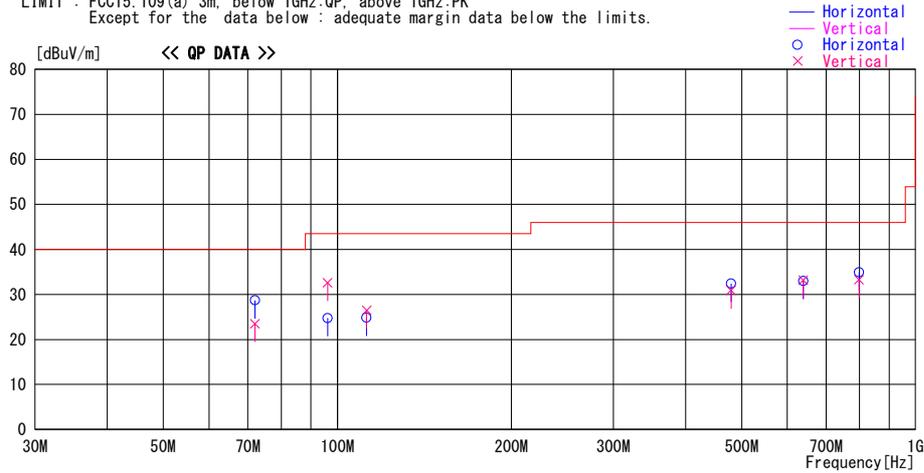
DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2012/04/16

Report No. : 32HE0178-HO
Temp./Humi. : 24deg. C / 40% RH
Engineer : Hironobu Ohnishi

Mode / Remarks : USB Data Com Mode, Worst axis: X

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
Except for the data below : adequate margin data below the limits.



Frequency [MHz]	Reading [dBuV]	DET	Antenna		Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]	Comment
			Factor [dB/m]	Loss& Gain [dB]							
72.024	52.9	QP	6.7	-30.9	28.7	109	261	Hori.	40.0	11.3	
72.024	47.7	QP	6.7	-30.9	23.5	70	180	Vert.	40.0	16.5	
96.134	46.1	QP	9.2	-30.6	24.7	238	185	Hori.	43.5	18.8	
96.134	54.0	QP	9.2	-30.6	32.6	183	100	Vert.	43.5	10.9	
112.325	43.4	QP	11.8	-30.4	24.8	149	165	Hori.	43.5	18.7	
112.325	45.1	QP	11.8	-30.4	26.5	156	100	Vert.	43.5	17.0	
479.316	40.8	QP	18.1	-26.5	32.4	129	100	Hori.	46.0	13.6	
479.316	39.3	QP	18.1	-26.5	30.9	12	162	Vert.	46.0	15.1	
639.089	38.4	QP	19.9	-25.3	33.0	142	145	Hori.	46.0	13.0	
639.089	38.6	QP	19.9	-25.3	33.2	21	111	Vert.	46.0	12.8	
798.300	37.3	QP	22.0	-24.4	34.9	132	125	Hori.	46.0	11.1	
798.300	35.7	QP	22.0	-24.4	33.3	54	111	Vert.	46.0	12.7	

CHART: WITH FACTOR ANT TYPE: -30MHz: LOOP, 30-300MHz: BICONICAL, 300MHz-1000MHz: LOGPERIODIC, 1000MHz-: HORN
CALCULATION: RESULT = READING + ANT FACTOR + LOSS (CABLE+ATTEN.) - GAIN (AMP)

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission
(Below 1GHz)

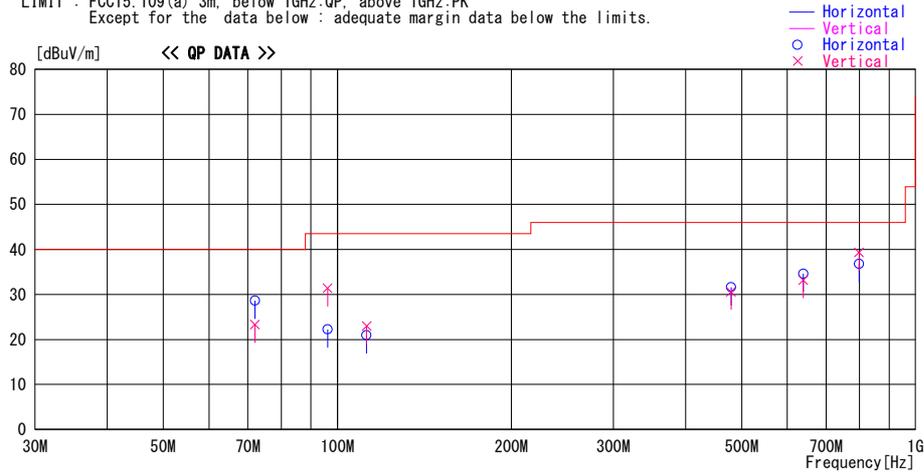
DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2012/04/16

Report No. : 32HE0178-HO
Temp./Humi. : 24deg. C / 40% RH
Engineer : Hironobu Ohnishi

Mode / Remarks : Standby Mode, Worst axis: X

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
Except for the data below : adequate margin data below the limits.



Frequency [MHz]	Reading [dBuV]	DET	Antenna		Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]	Comment
			Factor [dB/m]	Loss& Gain [dB]							
72.024	52.8	QP	6.7	-30.9	28.6	108	264	Hori.	40.0	11.4	
72.024	47.5	QP	6.7	-30.9	23.3	51	209	Vert.	40.0	16.7	
96.134	43.6	QP	9.2	-30.6	22.2	233	200	Hori.	43.5	21.3	
96.134	52.8	QP	9.2	-30.6	31.4	158	100	Vert.	43.5	12.1	
112.325	39.5	QP	11.8	-30.4	20.9	140	162	Hori.	43.5	22.6	
112.325	41.6	QP	11.8	-30.4	23.0	159	100	Vert.	43.5	20.5	
479.316	40.0	QP	18.1	-26.5	31.6	125	100	Hori.	46.0	14.4	
479.316	39.0	QP	18.1	-26.5	30.6	11	162	Vert.	46.0	15.4	
639.089	40.0	QP	19.9	-25.3	34.6	147	146	Hori.	46.0	11.4	
639.089	38.6	QP	19.9	-25.3	33.2	20	109	Vert.	46.0	12.8	
798.300	39.2	QP	22.0	-24.4	36.8	125	144	Hori.	46.0	9.2	
798.300	41.7	QP	22.0	-24.4	39.3	62	110	Vert.	46.0	6.7	

CHART: WITH FACTOR ANT TYPE: -30MHz: LOOP, 30-300MHz: BICONICAL, 300MHz-1000MHz: LOGPERIODIC, 1000MHz-: HORN
CALCULATION: RESULT = READING + ANT FACTOR + LOSS (CABLE+ATTEN.) - GAIN (AMP)

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission (Above 1GHz)

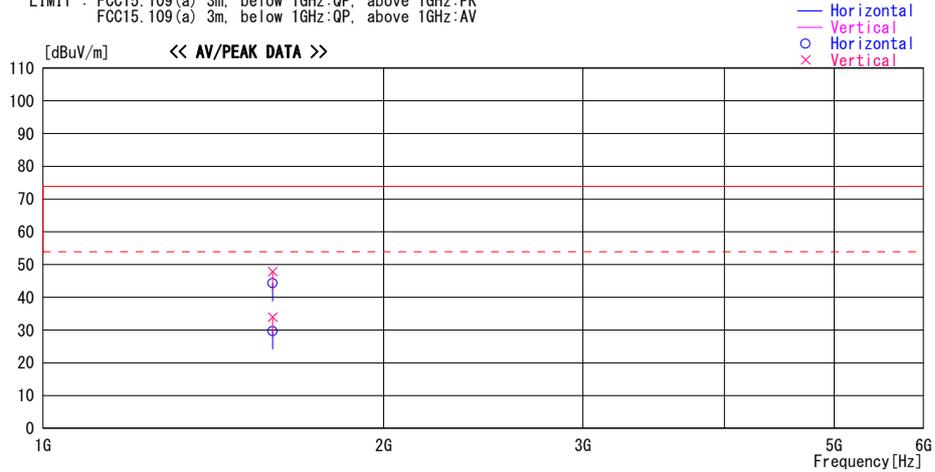
DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2012/04/16

Report No. : 32HE0178-HO
Temp./Humi. : 24deg. C / 40% RH
Engineer : Hironobu Ohnishi

Mode / Remarks : USB Data Com Mode, Worst axis: X

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]	Comment
			Factor [dB/m]	Gain [dB]							
1595.833	51.6	PK	26.2	-33.5	44.3	63	109	Hori.	73.9	29.6	
1595.833	37.0	AV	26.2	-33.5	29.7	63	109	Hori.	53.9	24.2	
1595.833	55.2	PK	26.2	-33.5	47.9	60	133	Vert.	73.9	26.0	
1595.833	41.3	AV	26.2	-33.5	34.0	60	133	Vert.	53.9	19.9	

CHART: WITH FACTOR ANT TYPE: -30MHz: LOOP, 30-300MHz: BICONICAL, 300MHz-1000MHz: LOGPERIODIC, 1000MHz-: HORN
CALCULATION: RESULT = READING + ANT FACTOR + LOSS(CABLE+ATTEN.) - GAIN(AMP)

*The limit is rounded down to one decimal place.
*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission
(Above 1GHz)

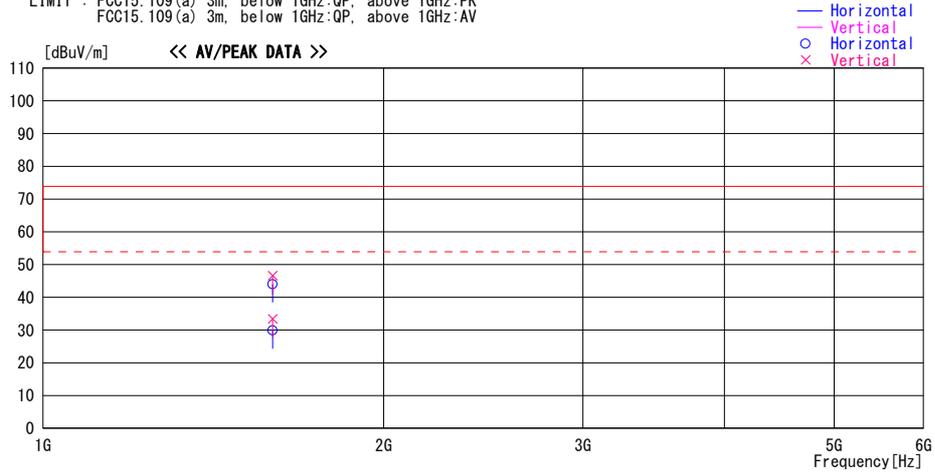
DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2012/04/16

Report No. : 32HE0178-HO
Temp./Humi. : 24deg. C / 40% RH
Engineer : Hironobu Ohnishi

Mode / Remarks : Standby Mode, Worst axis: X

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]	Comment
			Factor [dB/m]	Gain [dB]							
1595.833	51.3	PK	26.2	-33.5	44.0	65	108	Hori.	73.9	29.9	
1595.833	37.2	AV	26.2	-33.5	29.9	65	108	Hori.	53.9	24.0	
1595.833	53.9	PK	26.2	-33.5	46.6	54	134	Vert.	73.9	27.3	
1595.833	40.7	AV	26.2	-33.5	33.4	54	134	Vert.	53.9	20.5	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN
CALCULATION:RESULT = READING + ANT FACTOR + LOSS(CABLE+ATTEN.) - GAIN(AMP)

*The limit is rounded down to one decimal place.
*The test result is rounded off to one or two decimal places, so some differences might be observed.

APPENDIX 2: Test instruments

EMI Test Instruments

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
MAEC-01	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 10m	DA-06881	RE/CE	2011/07/10 * 12
MOS-27	Thermo-Hygrometer	CUSTOM	CTH-201	A08Q26	RE/CE	2012/02/08 * 12
MJM-01	Measure	KDS	ES19-55	-	RE/CE	-
COTS-MEMI	EMI measurement program	TSJ	TEPTO-DV	-	RE/CE	-
MTR-08	Test Receiver	Rohde & Schwarz	ESCI	100767	RE/CE	2011/08/11 * 12
KBA-05	Biconical Antenna	Schwarzbeck	BBA9106	2513	RE	2011/11/23 * 12
KLA-04	Logperiodic Antenna	Schwarzbeck	USLP9143	361	RE	2011/11/23 * 12
MAT-08	Attenuator(6dB)	Weinschel Corp	2	BK7971	RE	2011/11/02 * 12
MCC-02	Coaxial Cable	Suhner/storm/Agilent /TSJ	-	-	RE	2011/09/17 * 12
MPA-19	Pre Amplifier	MITEQ	MLA-10K01-B01-35	1237616	RE	2012/02/20 * 12
MSA-04	Spectrum Analyzer	Agilent	E4448A	US44300523	RE	2012/04/06 * 12
MHA-05	Horn Antenna 1-18GHz	Schwarzbeck	BBHA9120D	253	RE	2011/06/19 * 12
MCC-133	Microwave Cable	HUBER+SUHNER	SUCOFLEX104	336164/4(1m) / 340640(5m)	RE	2011/09/07 * 12
MPA-10	Pre Amplifier	Agilent	8449B	3008A02142	RE	2012/01/25 * 12
MLS-06	LISN(AMN)	Schwarzbeck	NSLK8127	8127363	CE(EUT)	2012/02/06 * 12
MLS-03	LISN(AMN)	Schwarzbeck	NSLK8127	8127384	CE(AE)	2012/03/01 * 12
MTA-30	Terminator	TME	CT-01	-	CE	2012/01/11 * 12
MCC-03	Coaxial Cable	Fujikura/Suhner/TSJ	5D-2W(20m)/ 3D-2W(7.5m)/ RG400u(1.5m)/RFM- E421(Switcher)	-/01068(Switcher)	CE	2012/01/22 * 12
MAT-64	Attenuator(13dB)	JFW Industries, Inc.	50FP-013H2 N	-	CE	2012/01/28 * 12

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test Item:

CE: Conducted emission

RE: Radiated emission

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8116

Facsimile : +81 596 24 8124